Substitute for form 1449A/PTO **INFORMATION DISCLOSURE STATEMENT BY APPLICANT** *(Use as many Sheets as necessary)* Sheet 1 of 1	*Complete if Known*	
	Application Number	10/014278
	Filing Date	December 11, 2001
	First Named Inventor	Hedin et al.
	Group Art Unit	2877
	Examiner Name	Lee, Andrew
	Attorney Docket No: 1010.8123U1	

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
ah	4,170,416	10/09/1979	Fencil			
	4,515,478	05/07/1985	Ballard et al.			
	4,566,794	01/28/1986	Hanse			

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Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T²

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
	✓	Office Action dated March 10, Application Serial No. 10/014,277	

EXAMINER [signature] DATE CONSIDERED 5/11/05

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional) ² Applicant is to place a check mark here if English language Translation is attached

INFORMATION DISCLOSURE STATEMENT

PTO Form 1449

Docket Number	Serial Number
980.1123US01	10/014278
Applicant(s)	
Hedin et al..	
Filing Date	**Group Art Unit**
12/11/01	2878

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE (IF APPROPRIATE)
		4,173,442	11/06/79	Snyder			
		5,428,700	06/27/95	Hall			
		6,233,263	05/15/01	Chang-Hasnain et al.			

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EXAMINER INITIALS	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO
		95/20144	07/27/95	WIPO				
		00/23764	04/27/00	WIPO				
		62242378	10/22/87	Japan			Abstract	
		05102589	04/23/93	Japan			Abstract	
		02039582	02/08/90	Japan			Abstract	
		02153583	06/13/90	Japan			Abstract	
		0818859	01/14/98	EPO				

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		International Search Report for PCT/US02/17299

Examiner:	Date Considered: 5/16/05

INFORMATION DISCLOSURE STATEMENT PTO Form 1449	D cket Number 980.1123US01	Serial Number 10/014278
	Applicant(s) Hedin et al.	
	Filing Dat December 11, 2001	Group Art Unit 2878

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ath		4,896,325	01/23/90	Coldren			
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							YES	NO

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ath		M. Oberg et al., "74 nm Wavelength Tuning Range of an InGaAsP Vertical Grating Assisted Codirectional Coupler Laser with Rear Sampled Grating Reflector," *IEEE Photonics Technology Letters*, 5(7):735-738 (July 1993).
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		Derickson, "Static Fizaeu Interferometer Wavelength Meter", *Fiber Optic Test and Measurement*, Prentice-Hall, ISBN 0-13-534330-5, 163-165 (1998).
		U.S. Application Serial No. 09/871,230, filed May 31, 2001.
		U.S. Application Serial No. 10/014,218, filed October 22, 2001.
		U.S. Application Serial No. 10/015,151, filed December 11, 2001.
		U.S. Application Serial No. 10/014,277, filed December 11, 2001.

Examiner:	Date Considered: 5/19/05

INFORMATION DISCLOSURE STATEMENT

PTO Form 1449

Docket Number	Serial Number
00980.1123-US-01	10/014278
Applicant(s)	
HEDIN et al.	
Filing Date	Group Art Unit
12/11/2001	2878

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ah		6,186,937	02/13/01	Ackerman et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO

OTHER DOCUMENTS

Examiner:	Date Considered: 6/7/05